



EMI TEST REPORT

Test Report No. : 29EE0229-HO

Applicant : Sharp Corporation, Communication Systems Group.
Type of Equipment : Cellular Phone
Model No. : CDMA SH002
FCC ID : APYHRO00097
Test regulation : FCC Part 15 Subpart B 2009 Class B
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

March 24, 2009

Tested by:

Katsunori Okai
EMC Services

Approved by :

Minoru Yamanaka
Assistant Manager of EMC Services



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.

*As for the range of Accreditation in NVLAP, you may refer to the WEB address,

<http://uljapan.co.jp/emc/nvlap.html>

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

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MF060b (09.01.08)

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SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Group.
Brand Name : SHARP
Address : 2-13-1, Iida Hachihonmatsu, Higashi-Hiroshima City, Hiroshima,
739-0192 Japan
Telephone Number : +81-82-420-1630
Facsimile Number : +81-82-420-1624
Contact Person : Hachiroh Hidaka

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : CDMA SH002
Serial No. : SSHCN000812
Rating : AC 120V/60Hz, DC4.0V
Receipt Date of Sample : March 19, 2009
Country of Mass-production : Japan
Condition of EUT : Production prototype
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: CDMA SH002 is 1XEV-DO Hybrid CDMA Tri-Band Cellular Phone.

CDMA SH002 has Bluetooth wireless interface technology for establishing contact and transmitting data with certain devices. FeliCa technology enabled easy changing and payments as Mobile Wallet. (Note: FeliCa does not operate in USA)

Clock frequency : 32.768kHz, 19.2MHz, 384MHz

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B 2009, final revised on February 27, 2009
Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	ANSI C63.4: 2003 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 13.9dB, 0.26825MHz, L [AV] 9.5dB, 0.51803MHz, N	Complied
Radiated emission	ANSI C63.4: 2003 8. Radiated emission measurements	Class B	N/A	4.5dB, 720.003MHz, QP, Horizontal	Complied
*Note: UL Japan, Inc's EMI Work Procedure QPM05.					

3.3 Additions or deviations to standards

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room	Conducted emission	Radiated emission (10m*)			Radiated emission (3m*)			Radiated emission (3m*)	
	150kHz- 30MHz	9kHz- 30MHz	30MHz- 300MHz	300MHz- 1GHz	9kHz- 30MHz	30MHz- 300MHz	300MHz- 1GHz	1GHz- 18GHz	18GHz- 40GHz
No.1 semi-anechoic chamber (±)	3.7dB	3.1dB	4.4dB	4.2dB	3.2dB	3.8dB	3.9dB	5.9dB	6.1dB
No.2 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.4dB	4.0dB	5.9dB	6.1dB
No.3 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	4.6dB	4.0dB	5.9dB	6.1dB
No.4 semi-anechoic chamber (±)	3.7dB	-	-	-	3.2dB	3.9dB	3.9dB	5.9dB	6.1dB

*10m/3m = Measurement distance

Conducted emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

Refer to APPENDIX 1 to 3.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Cellular Phone	CDMA SH002	SSHCHN000812	SHARP	EUT
B	PC	DELL PP10L	8LH3H1X	DELL	-
C	Printer	BJF860	K10201	Canon	DOC
D	USB Mouse	DELL M05UOA	G0N00FiF	DELL	-
E	AC Adaptor(PC)	AA22850	-	DELL	-
F	micro SD Memory Card	64MB type	-	PANASONIC	-
G	Lithium-ion Battery	SH001UAA	-	SHARP	3.7V, 800mA (3.0Wh)

List of cables used

No.	Name	Length (m)	Shield		Remark
			Cable	Connector	
1	USB Data Cable	0.8	Shielded	Shielded	-
2	Parallel Cable	2.0	Shielded	Shielded	-
3	AC Power Cable (Printer)	2.0	Unshielded	Unshielded	-
4	Mouse Cable	1.9	Unshielded	Unshielded	-
5	AC Charger Cable (PC)	1.9	Unshielded	Unshielded	-
6	AC Power Cable (PC)	0.9	Unshielded	Unshielded	-

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No.1 semi anechoic chamber.
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 1.

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector. The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: March 24, 2009

Test engineer: Katsunori Okai

SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No.1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.
Photographs of the set up are shown in Appendix 1.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz -2000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.
The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.
The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 1MHz AV *1): RBW:1MHz/VBW:10Hz

*1) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: March 24, 2009

Test engineer: Katsunori Okai

APPENDIX 1: Photographs of test setup

Conducted Emission

This page has been submitted for a separate exhibit.

Radiated Emission

This page has been submitted for a separate exhibit.

Worst Case Position (Horizontal: X-axis/ Vertical:X-axis)

This page has been submitted for a separate exhibit.

Conducted Emission

DATA OF CONDUCTED EMISSION TEST

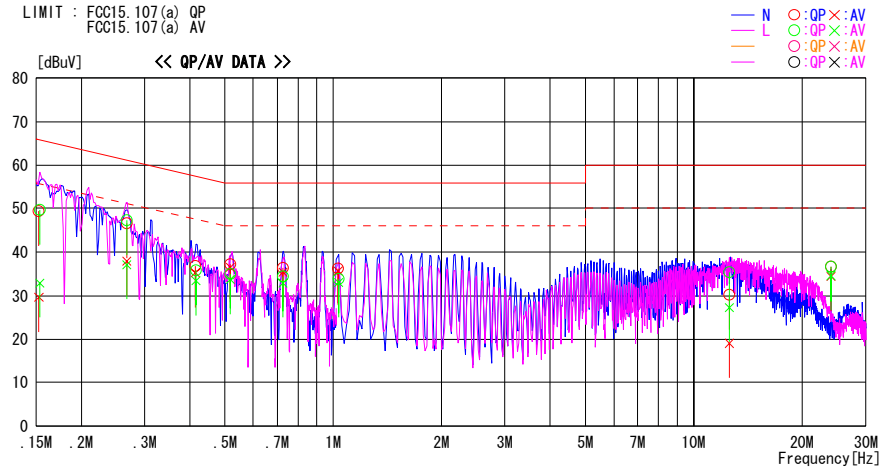
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/03/24

Company : Sharp Corporation
Kind of EUT : Cellular phone
Model No. : CDMA SH002
Serial No. : SSHCN00812

Report No. : 29EE0229-HO
Power : AC 120V / 60Hz
Temp./Humi. : 23deg.C. / 30%
Engineer : Katsunori Okai

Mode / Remarks : Standby mode

LIMIT : FCC15.107(a) QP
FCC15.107(a) AV



Frequency [MHz]	Reading Level		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15266	49.2	29.4	0.2	49.4	29.6	65.9	55.9	16.5	26.3	N	
0.26802	46.3	37.6	0.3	46.6	37.9	61.2	51.2	14.6	13.3	N	
0.41451	36.5	34.9	0.3	36.8	35.2	57.6	47.6	20.8	12.4	N	
0.51803	36.9	36.2	0.3	37.2	36.5	56.0	46.0	18.8	9.5	N	
0.72665	36.0	35.0	0.4	36.4	35.4	56.0	46.0	19.6	10.6	N	
1.03190	35.8	35.3	0.4	36.2	35.7	56.0	46.0	19.8	10.3	N	
12.54308	28.5	17.4	1.7	30.2	19.1	60.0	50.0	29.8	30.9	N	
0.15349	49.4	32.7	0.2	49.6	32.9	65.8	55.8	16.2	22.9	L	
0.26825	47.0	36.8	0.3	47.3	37.1	61.2	51.2	13.9	14.1	L	
0.41593	35.5	33.1	0.3	35.8	33.4	57.5	47.5	21.7	14.1	L	
0.51810	34.7	33.4	0.3	35.0	33.7	56.0	46.0	21.0	12.3	L	
0.72554	34.0	32.5	0.4	34.4	32.9	56.0	46.0	21.6	13.1	L	
1.03390	33.5	32.6	0.4	33.9	33.0	56.0	46.0	22.1	13.0	L	
12.54384	33.7	25.6	1.7	35.4	27.3	60.0	50.0	24.6	22.7	L	
24.01301	34.1	31.9	2.5	36.6	34.4	60.0	50.0	23.4	15.6	N	
24.01302	34.1	32.1	2.5	36.6	34.6	60.0	50.0	23.4	15.4	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT [dBuV] = READING [dBuV] + C. F. [dB] (LISN LOSS + CABLE LOSS)
Except for the above table: adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission

DATA OF RADIATED EMISSION TEST

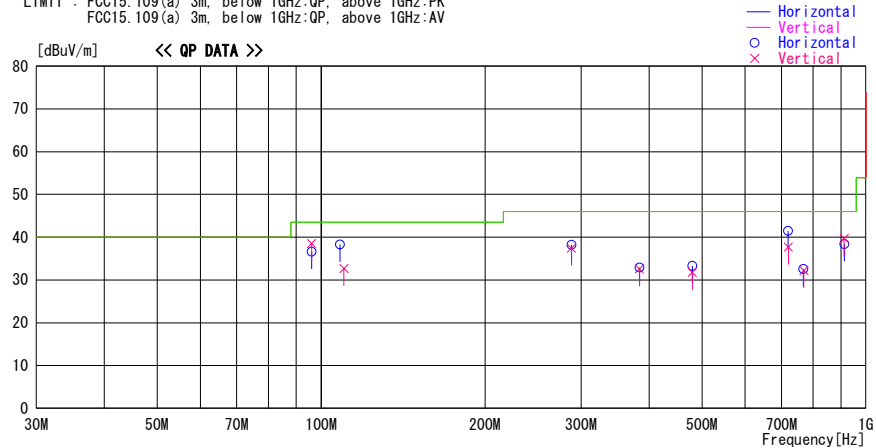
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/03/24

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : CDMA SH002
Serial No. : SSHCN00812

Report No. : 29EE0229-HO
Power : AC 120V / 60Hz
Temp./Humi. : 23deg.C. / 30%
Engineer : Katsunori Okai

Mode / Remarks : USB Data Com mode, Worst-axis(Hori:X, Vert:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna		Level	Polar.	Limit	Margin	Comment
			Factor	Gain					
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]		[dBuV/m]	[dB]	
96.006	47.1	QP	9.5	-20.0	36.6	Hori.	43.5	6.9	
96.009	49.0	QP	9.5	-20.0	38.5	Vert.	43.5	5.0	
108.341	46.9	QP	11.3	-19.9	38.3	Hori.	43.5	5.2	
110.074	40.9	QP	11.6	-19.8	32.7	Vert.	43.5	10.8	
288.000	35.2	QP	19.6	-17.4	37.4	Vert.	46.0	8.6	
288.012	36.0	QP	19.6	-17.4	38.2	Hori.	46.0	7.8	
384.001	34.0	QP	15.9	-17.0	32.9	Hori.	46.0	13.1	
384.006	33.7	QP	15.9	-17.0	32.6	Vert.	46.0	13.4	
480.008	30.8	QP	18.0	-17.0	31.8	Vert.	46.0	14.2	
480.016	32.3	QP	18.0	-17.0	33.3	Hori.	46.0	12.7	
720.003	36.2	QP	20.9	-15.6	41.5	Hori.	46.0	4.5	
720.500	32.4	QP	20.9	-15.6	37.7	Vert.	46.0	8.3	
768.005	26.5	QP	21.4	-15.3	32.6	Hori.	46.0	13.4	
769.005	26.1	QP	21.4	-15.3	32.2	Vert.	46.0	13.8	
912.004	32.6	QP	21.4	-14.3	39.7	Vert.	46.0	6.3	
913.033	31.1	QP	21.5	-14.2	38.4	Hori.	46.0	7.6	

CHART:WITH FACTOR ANT TYPE: ~30MHz:LOOP, 30~300MHz:BICONICAL, 300MHz~1000MHz:LOGPERIODIC, 1000MHz~:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission

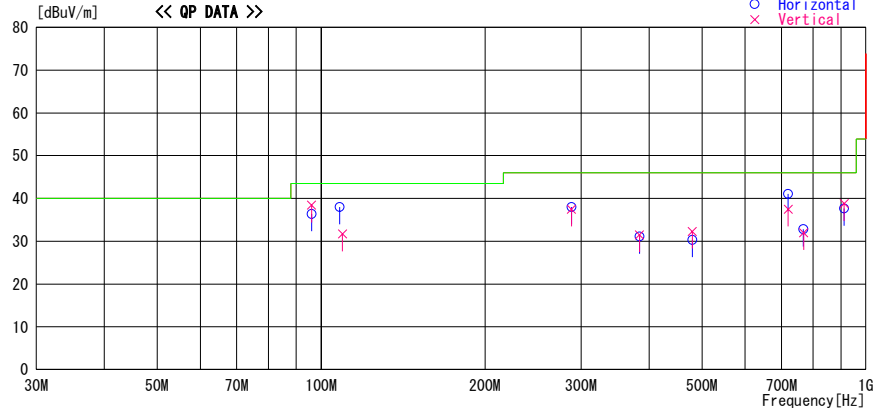
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/03/24

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : CDMA SH002
Serial No. : SSHCN00812
Report No. : 29EE0229-HO
Power : AC 120V / 60Hz
Temp./Humi. : 23deg.C. / 30%
Engineer : Katsunori Okai

Mode / Remarks : Standby mode, Worst-axis(Hori:X, Vert:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna		Level	Polar.	Limit	Margin	Comment
			Factor	Gain					
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]		[dBuV/m]	[dB]	
96.001	48.9	QP	9.5	-20.0	38.4	Vert.	43.5	5.1	
96.003	46.9	QP	9.5	-20.0	36.4	Hori.	43.5	7.1	
108.051	46.6	QP	11.3	-18.9	38.0	Hori.	43.5	5.5	
109.473	40.1	QP	11.5	-19.9	31.7	Vert.	43.5	11.8	
288.001	35.3	QP	19.6	-17.4	37.5	Vert.	46.0	8.5	
288.005	35.8	QP	19.6	-17.4	38.0	Hori.	46.0	8.0	
384.006	32.2	QP	15.9	-17.0	31.1	Hori.	46.0	14.9	
384.007	32.6	QP	15.9	-17.0	31.5	Vert.	46.0	14.5	
480.005	29.3	QP	18.0	-17.0	30.3	Hori.	46.0	15.7	
480.010	31.3	QP	18.0	-17.0	32.3	Vert.	46.0	13.7	
720.006	35.8	QP	20.9	-15.6	41.1	Hori.	46.0	4.9	
720.011	32.2	QP	20.9	-15.6	37.5	Vert.	46.0	8.5	
768.003	26.7	QP	21.4	-15.3	32.8	Hori.	46.0	13.2	
768.200	25.9	QP	21.4	-15.3	32.0	Vert.	46.0	14.0	
912.002	31.7	QP	21.4	-14.3	38.8	Vert.	46.0	7.2	
912.131	30.6	QP	21.4	-14.3	37.7	Hori.	46.0	8.3	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission

DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/03/24

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Kind of EUT : Cellular Phone
Model No. : CDMA SH002
Serial No. : SSHCN00812
Report No. : 29EE0229-HO
Power : AC 120V / 60Hz
Temp./Humi. : 23deg. C. / 30%
Engineer : Katsunori Okai

Mode / Remarks : USB Data Com mode, Worst-axis(Hori:X , Vert:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna		Level	Polar.	Limit	Margin	Comment
			Factor	Gain					
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]		[dBuV/m]	[dB]	
1006.613	56.7	PK	24.4	-35.6	45.5	Hori.	73.9	28.4	
1006.613	52.1	AV	24.4	-35.6	40.9	Hori.	53.9	13.0	
1006.615	59.5	PK	24.4	-35.6	48.3	Vert.	73.9	25.6	
1006.615	53.1	AV	24.4	-35.6	41.9	Vert.	53.9	12.0	
1152.000	51.2	PK	24.8	-35.3	40.7	Vert.	73.9	33.2	
1152.000	48.2	PK	24.8	-35.3	37.7	Hori.	73.9	36.2	
1152.000	37.7	AV	24.8	-35.3	27.2	Hori.	53.9	26.7	
1152.000	44.2	AV	24.8	-35.3	33.7	Vert.	53.9	20.2	

CHART:WITH FACTOR ANT TYPE:-30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz:-HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.

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Radiated Emission

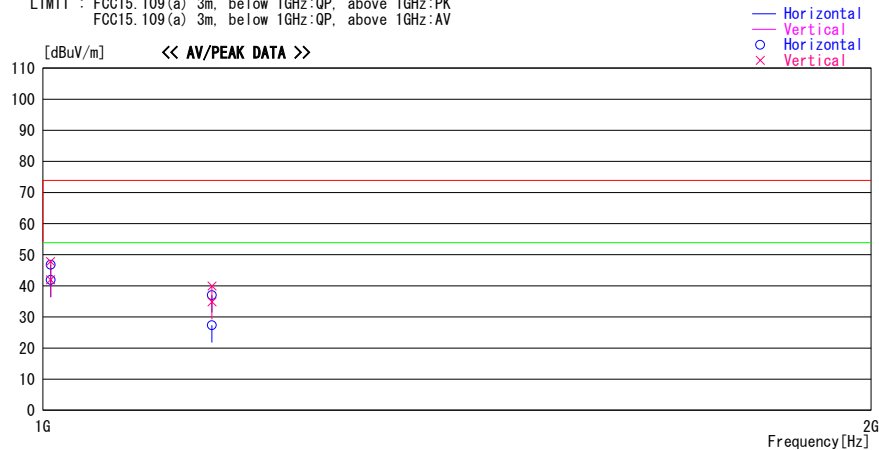
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Power : AC 120V / 60Hz
Temp./Humi. : 23deg. C. / 30%
Engineer : Katsunori Okai

Mode / Remarks : Standby mode, Worst-axis(Hori:X, Vert:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency	Reading	DET	Antenna	Loss&	Level	Polar.	Limit	Margin	Comment
			Factor	Gain					
[MHz]	[dBuV]		[dB/m]	[dB]	[dBuV/m]		[dBuV/m]	[dB]	
1006.610	59.1	PK	24.4	-35.6	47.9	Vert.	73.9	26.0	
1006.610	53.2	AV	24.4	-35.6	42.0	Vert.	53.9	11.9	
1006.613	53.1	AV	24.4	-35.6	41.9	Hori.	53.9	12.0	
1006.613	58.0	PK	24.4	-35.6	46.8	Hori.	73.9	27.1	
1152.000	50.5	PK	24.8	-35.3	40.0	Vert.	73.9	33.9	
1152.000	47.5	PK	24.8	-35.3	37.0	Hori.	73.9	36.9	
1152.000	37.8	AV	24.8	-35.3	27.3	Hori.	53.9	26.6	
1152.000	45.3	AV	24.8	-35.3	34.8	Vert.	53.9	19.1	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz-:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 3: Test instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2008/10/29 * 12
MBA-01	Biconical Antenna	Schwarzbeck	BBA9106	VHA9103200 7	RE	2008/11/12 * 12
MLA-09	Logperiodic Antenna	Schwarzbeck	USLP9143B	9143B006	RE	2008/11/12 * 12
MAT-06	Attenuator(6dB)	Weinschel Corp	2	BL1069	RE	2008/11/14 * 12
MCC-01	Coaxial Cable 0.1-3000MHz	Suhner/storm/Agilent /TSJ	-	-	RE	2008/10/02 * 12
MPA-04	Pre Amplifier	Agilent	8447D	2944A09965	RE	2008/07/23 * 12
MTR-01	Test Receiver	Rohde & Schwarz	ES140	100084	RE/CE	2008/12/01 * 12
CUST-MSTW-14	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MOS-01	Digital Humidity Indicator	N.T	NT-1800	MOS01	RE/CE	2009/02/06 * 12
MJM-01	Measure	KDS	ES19-55	-	RE/CE	-
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2009/01/31 * 12
MCC-18	Microwave Cable 1G-26.5GHz	Suhner	SUCOFLEX 104	233010(1m) / 292410(5m)	RE	2008/09/09 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2009/02/12 * 12
MLS-06	LISN(AMN)	Schwarzbeck	NSLK8127	8127383	CE(EUT)	2008/06/27 * 12
MLS-03	LISN(AMN)	Schwarzbeck	NSLK8127	8127384	CE(AE)	2008/07/01 * 12
MTA-06	Terminator	MCL	BTRM-50	1 9951	CE	2009/02/17 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/Agilent/TSJ	-	-	CE	2008/12/16 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with traceable calibrations. Each calibration is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted emission

RE: Radiated emission

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